

**Search Notes**

Application/Control No.

10/764,914

Examiner

Hiep Nguyen

Applicant(s)/Patent under  
Reexamination

SIBRAI ET AL.

Art Unit

2816

**SEARCHED**

Class	Subclass	Date	Examiner
327	337	02.25.05	Hiep
	393	T	T
	396	T	
	592		
331	158		
330	86		
331	25	↓	↓

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST See attachment	02.25.05	Hiep
Consulted with Tuan Lam	02.25.05	Hiep

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner